

Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office				Attorney Docket No.: RAL 9-1999-0133		Serial No.: To Be Assigned	
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Applicants: John C. Fluke, Joel M. Yarborough			
				Filing Date: Concurrently Herewith		GAU:	
U.S. PATENT DOCUMENTS							
Examiner Initials		Document No.	Date	Name	Class	Subclass	Filing Date if Appropriate
EBK	1	5,881,213	03/09/99	Shaw et al.	395	114	
	2	5,841,250	11/24/98	Korenage et al.	318	135	
EBK	3	5,815,653	09/29/98	You et al.	395	183.14	
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EBK	7	5,297,150	03/22/94	Clark	371	19	
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EBK	14	Paredes, <i>Efficient File Format for the Abridged Description of Hardware</i> , IBM Technical Bulletin, V. 41, N. 1, January 1998, pp. 191-198					
EBK	15	Slane, <i>Dynamically Skipped Code Using Jump/Branch Debug Instruction</i> , IBM Technical Bulletin, V. 37, N. 4, April 1994, pp. 429-430					
	16	Brabee et al., <i>Triggering Scheme to Trap Trace Data</i>, Research Disclosure N. 324, April 1991					
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EBK	20	Jordan et al., <i>Distributed Trace Formatter: A Program to Format Tract Data in Any Format and Any Language</i> , IBM Technical Bulletin, September 1991, pp. 295-297					
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EBK	22	Bohrer et al., <i>Method to Provide Changes to the Aix Operating System Kernel for Multi-Process Debugging</i> , IBM Technical Bulletin, July 1990, pp. 276-278					
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Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EBK	26	Cianciosi et al., <i>Interactive Alter Display Instruction Trace Programming Aid</i> , IBM Technical Bulletin, August 1974, pp. 734-738
EBK	27	Memis et al., <i>On Line Debug Macro and Subroutine</i> , IBM Technical Bulletin, October 1971, pp. 1500-1503
EBK	28	Trace Library, http://www.cs.arizona.edu/xkernel/www/manual/section3-9.html , July 15, 1999, 1 p.
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EBK	30	Re: libc/printf.c, http://www.zendo.com/vandys/vsta-mail/6/0007.html , July 15, 1999, 1 p.

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		Document Number	Date	Country	Class	Subclass	Translation Yes / No
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